## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | IVANISEVIC ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0015265 A1	01-2006	Raich, Anne C.	702/022
*	В	US-6,836,532 B2	12-2004	Durst et al.	378/73
*	С	US-6,507,636 B1	01-2003	Lehmann, Christian W.	378/79
*	D	US-6,459,763 B1	. 10-2002	Koinuma et al.	378/71
*	E	US-2002/0067800 A1	06-2002	Newman et al.	378/73
*	F	US-6,327,334 B1	12-2001	Murray et al.	378/75
*	G	US-5,870,697	02-1999	Chandler et al.	702/179
	Н	US-			
	1	US-			
	,	US-			
	К	US-		•	
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ń				·	
	0					
	Р					
	Q	•				· · · · · · · · · · · · · · · · · · ·
	R	·				
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. D. Cullity and S. R. Stock, Elements of X-Ray Diffraction, third edition (New Jersey: Prentice Hall, 2001).
	V	Vidal et al., "Multivariate cluster analysis of trace elements and mineralogical components from some rural soils," Development and Application of Computer Techniques to Environmental Studies VI, Proceedings of Sixth International Conference ENVIROSOFT 1996, p. 215-224.
-	w	Infometrix, Inc., "Description of Pirouette Algorithms," Chemometrics Technical Note, 1993, p. 1-4.
	x	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.